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# MIL STD 883 TM 2017 Certification Test

## Student Assessment

(Revised MAR 2020)

Name: \_\_\_\_\_ Date: \_\_\_\_\_

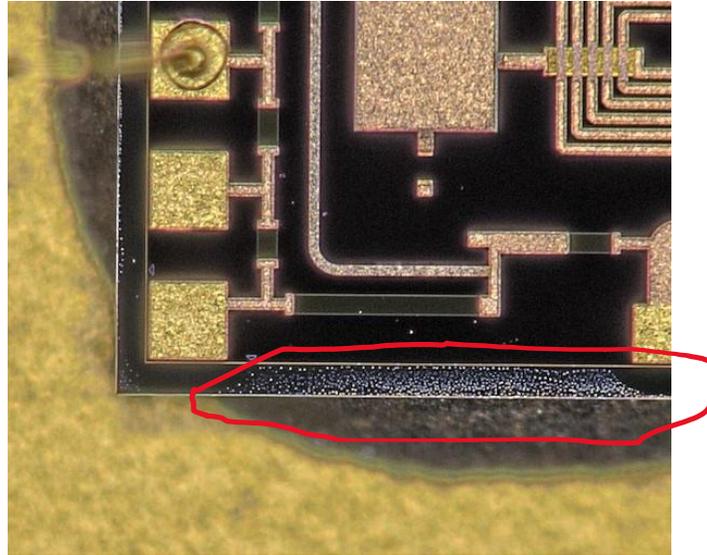
### PART 1 – True/False Questions

	TRUE	FALSE
1. Test Method 2017 is part of Mil-Std-883 visual inspection criteria	X	
2. Metallization voids on IC greater than 75 % are acceptable		X
3. A 100% epoxy fillet is required around the entire perimeter of an epoxy die bond		X
4. A heel crack at the junction of a wire bond is OK		X
5. 1.5X squash out on a 1 mil gold wire ball bond is ideal		X
6. Loose foreign material or particles are acceptable at Pre Cap		X
7. A crack at the edge of the die pointing away from the active area is acceptable	X	
8. All wires must have some loop for stress relief, unless noted on the drawing	X	
9. Lifted or peeling metal in a non-active area is acceptable		X
10. Bonds that are not completely within the boundaries of the package post are OK		X
11. A laser trim cut into a resistor more than 50% of the width is a reject	X	
12. A glassivation void that exposes two or more active metallization paths is OK		X
13. Residual epoxy on the surface of the IC or MMIC is acceptable		X
14. The diode inspection criteria is found in TM 2017		X
15. Inspection criteria for capacitors and resistors is found in TM 2010 Low Mag		X
16. Voids greater than 50% on an IC Metal run is cause for reject	X	
17. ESD precautions are not required at Pre Cap		X
18. Cracks in epoxy are OK provided they are less than 5 mils in length	X	
19. At Pre Cap high mag inspection must be performed first followed by low mag		X
20. High magnification IC inspection criteria is found in MIL-STD-750		X

## PART 2 – Multiple Choice/Essay Questions

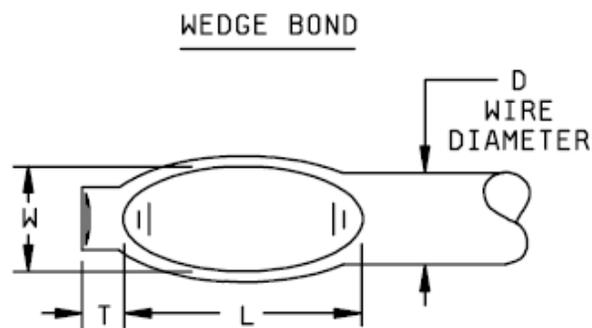
1. ACCEPT  REJECT  (Circle one and briefly explain why below.)

REASON: Resin bleed out wicked up onto MMIC



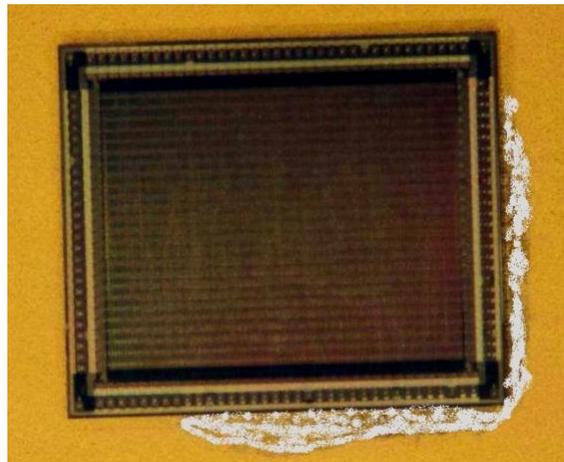
2. The maximum deformation on a thermosonic wedge bond (W) per TM 2017 is:

- A. 1.5 X the wire diameter  
B. 3.0 X the wire diameter  
 C. 2.0 X the wire diameter  
D. None of the above



3. Below is a photo of a silicon die with silver epoxy die attach material visible at the perimeter. Choose the following:

- A. ACCEPT: Epoxy visible around 50% of the perimeter
- B. REJECT: Too much epoxy visible
- C. REJECT: Insufficient die attach material visible
- D. ACCEPT: Epoxy visible on two non-adjacent sides



4. Draw a line from the device on the left matching the appropriate test method on the right :

- |                  |   |        |
|------------------|---|--------|
| A. DIODES        | → | TM2010 |
| B. MMICS AND ICS | → | TM2073 |
| C. RESISTORS     | → | TM2069 |
| D. WIREBONDS     | → | TM2017 |
| E. POWER MOSFETS | → | TM2032 |

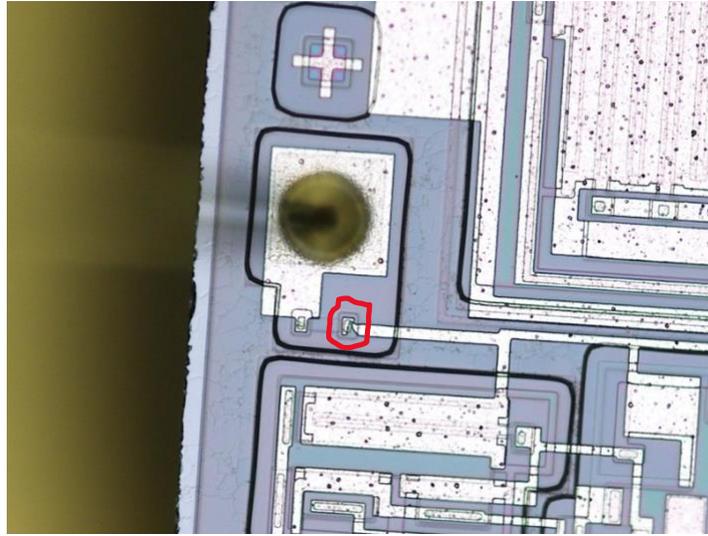
5. ACCEPT

**REJECT**

(Circle one and briefly explain why below.)

REASON:

METAL REDUCED 90% AT TOP OF VIA



6. ACCEPT

**REJECT**

(Circle one and briefly explain why below.)

REASON:

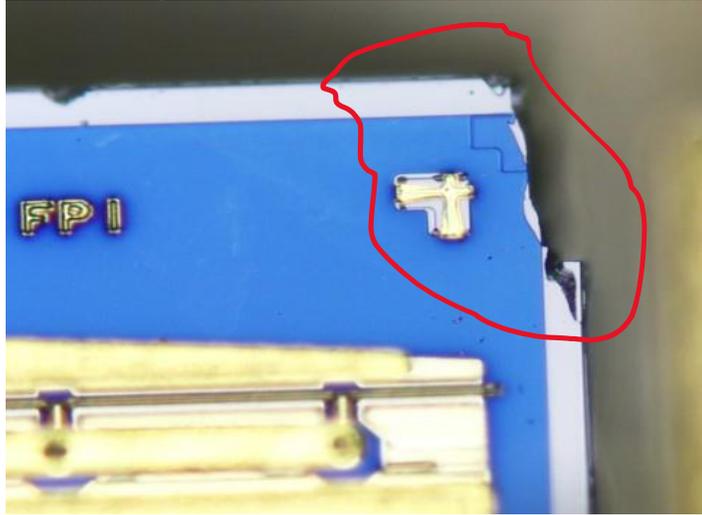
Wedge bond more than 50% off pad and shorted.



7. ACCEPT REJECT (Circle one and briefly explain why below.)

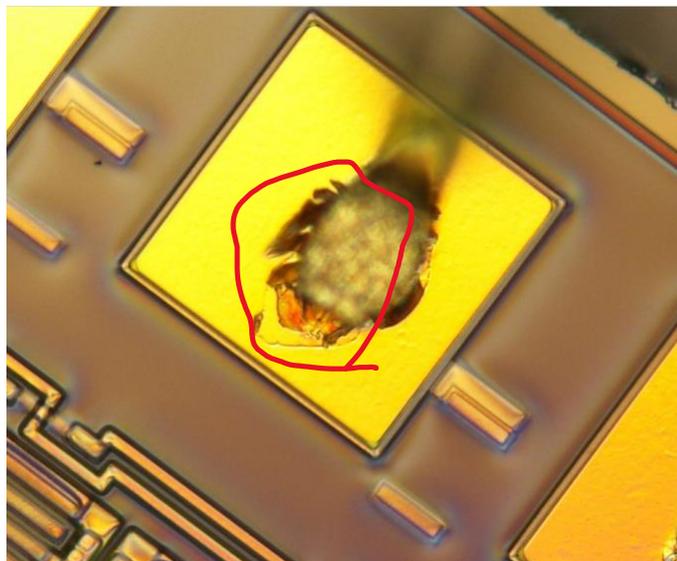
REASON:

Corner chipout OK not into active metal



8. ACCEPT REJECT (Circle one and briefly explain why below.)

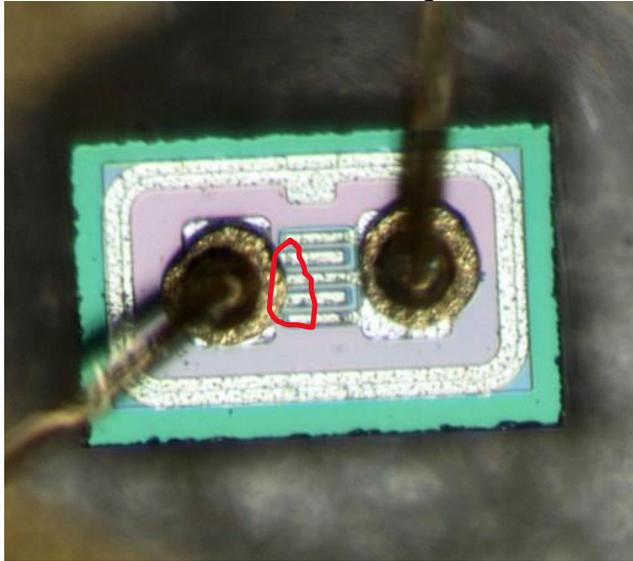
REASON: Wirebond on top of disturbed metal and bond pad crater.



9. ACCEPT  REJECT (Circle one and briefly explain why below.)

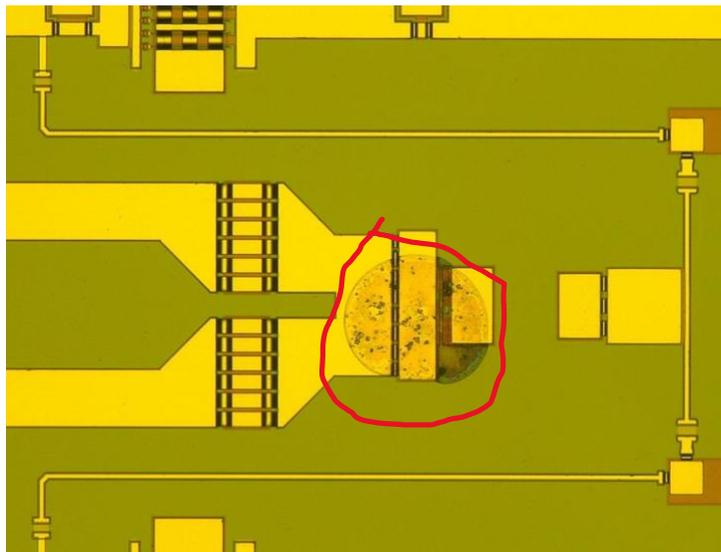
REASON:

Gold ball bond shorted to finger caused a shorted junction.



10. ACCEPT  REJECT (Circle one and briefly explain why below.)

REASON: Human contamination or "spittle "



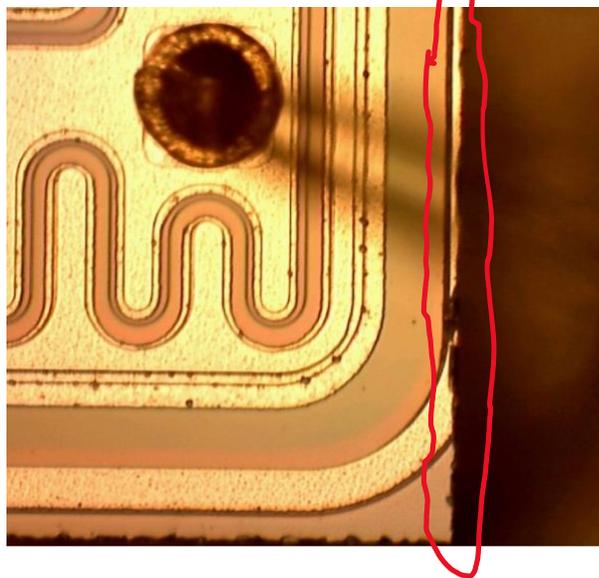
11. ACCEPT

**REJECT**

(Circle one and briefly explain why below.)

REASON:

A poorly aligned wafer saw cut on RHS cut through guard ring.



12. ACCEPT

**REJECT**

(Circle one and briefly explain why below.)

REASON: A void in metal run greater than 50%

